Power MOSFET

100 V, 4.8 m Ω , 145 A, Single N-Channel

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- NVMFS6B03NWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	100	V
Gate-to-Source Voltage			V_{GS}	±16	V
Continuous Drain Current R _{0,JC} (Notes 1, 2,		T _C = 25°C	I _D	145	Α
3)	Steady State	T _C = 100°C		102	
Power Dissipation		T _C = 25°C	P_{D}	198	W
R _{θJC} (Notes 1, 2)		T _C = 100°C		99	
Continuous Drain Cur-		T _A = 25°C	I _D	20	Α
rent $R_{\theta JA}$ (Notes 1, 2, 3)	Steady	T _A = 100°C	1	14	
Power Dissipation	State	T _A = 25°C	P _D	3.9	W
R _{θJA} (Notes 1 & 2)		T _A = 100°C		2.0	
Pulsed Drain Current	$T_A = 25$	°C, t _p = 10 μs	I _{DM}	520	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to + 175	°C
Source Current (Body Diode)			I _S	160	Α
Single Pulse Drain-to-Source Avalanche Energy (T _J = 25°C, V _{DD} = 50 V, V _{GS} = 10 V, $I_{L(pk)}$ = 60 A, L = 0.1 mH, R_G = 25 Ω)			E _{AS}	180	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.76	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	38	

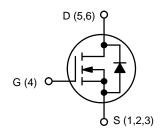
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



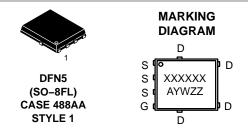
ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX		
100 V	4.8 m Ω @ 10 V	145 A		



N-CHANNEL MOSFET



A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						•	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				67.3		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{OS} = 0 \text{ V},$ $V_{DS} = 80 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$				10	
						100	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} = 16 V				100	nA
ON CHARACTERISTICS (Note 4)					-		
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$	= 250 μA	2.0		4.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	·			-8.1		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 20 A		3.8	4.8	mΩ
CHARGES, CAPACITANCES & GATE RESIS	STANCE		•			•	•
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 50 V			4200		pF
Output Capacitance	C _{OSS}				760		
Reverse Transfer Capacitance	C _{RSS}				31		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 10 \text{ V}, V_{DS} = 80 \text{ V}; I_{D} = 50 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$			58		nC
Threshold Gate Charge	Q _{G(TH)}				6.2		
Gate-to-Source Charge	Q _{GS}				19		
Gate-to-Drain Charge	Q_{GD}				17		
Plateau Voltage	V_{GP}				5.4		V
Gate Resistance	R_{G}				1.0		Ω
SWITCHING CHARACTERISTICS (Note 5)						•	•
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 10 \text{ V}, V_{DS} = 80 \text{ V},$ $I_D = 50 \text{ A}, R_G = 1.0 \Omega$			16		
Rise Time	t _r				46		ns
Turn-Off Delay Time	t _{d(OFF)}				29		
Fall Time	t _f				11		
DRAIN-SOURCE DIODE CHARACTERISTIC	S				-		
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 V$, $I_S = 50 A$	T _J = 25°C		0.9	1.2	14
			T _J = 125°C		0.8		V
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 25 \text{ A}$			67		
Charge Time	t _a				35		ns
Discharge Time	t _b				31		
Reverse Recovery Charge	Q _{RR}				120		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

^{5.} Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

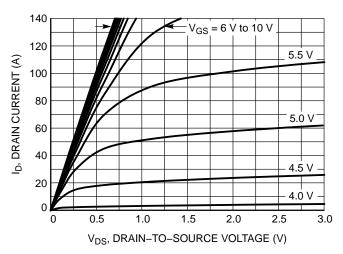


Figure 1. On-Region Characteristics

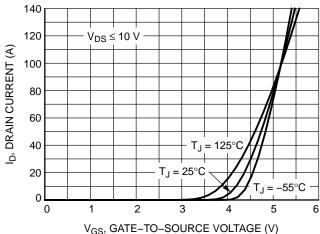


Figure 2. Transfer Characteristics

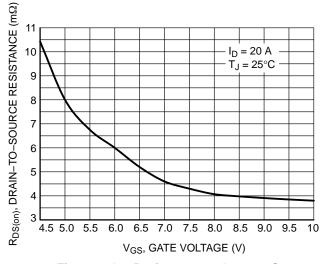


Figure 3. On–Resistance vs. Gate–to–Source Voltage

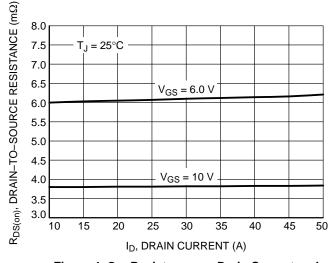


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

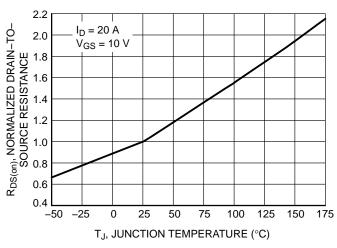


Figure 5. On–Resistance Variation with Temperature

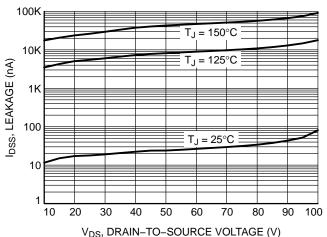


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

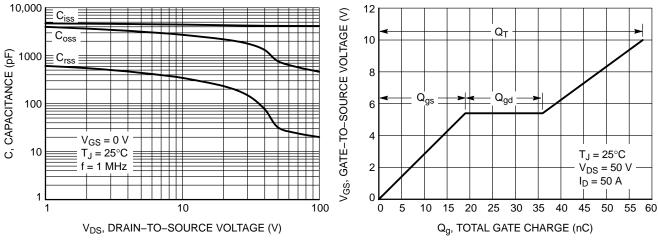


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

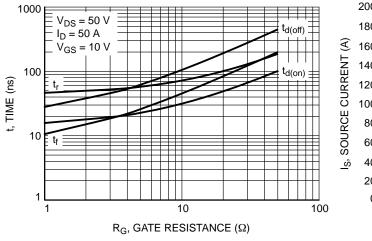


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

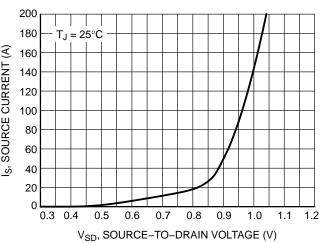


Figure 10. Diode Forward Voltage vs. Current

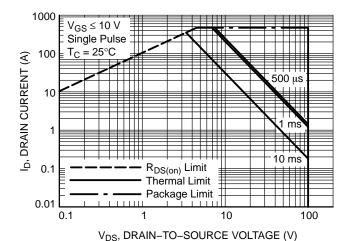


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

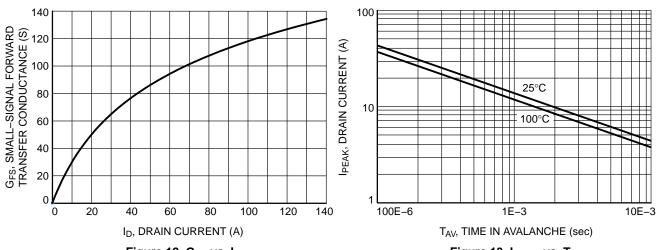


Figure 12. G_{FS} vs. I_D

Figure 13. I_{PEAK} vs. T_{AV}

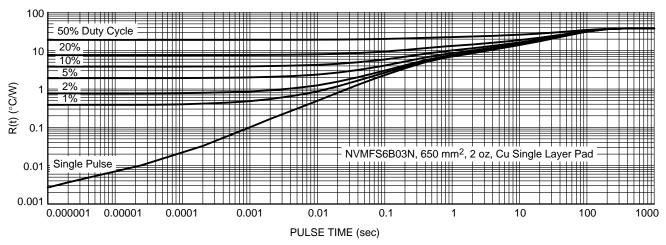


Figure 14. Thermal Response

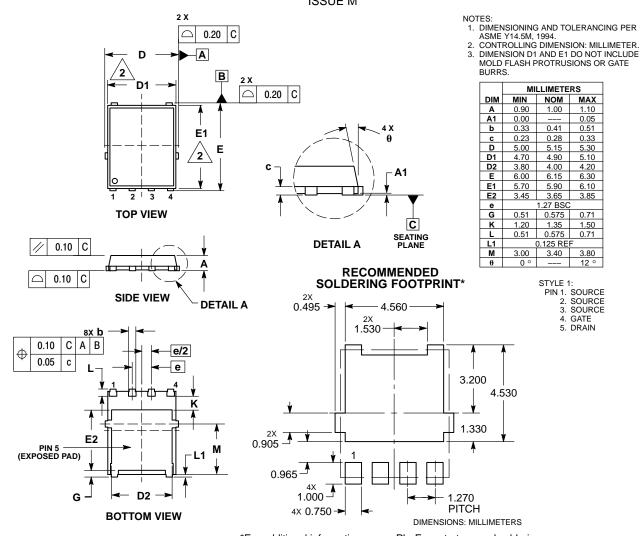
DEVICE ORDERING INFORMATION

Device	Marking	Package	Shipping [†]
NVMFS6B03NT1G	6B03N	DFN5 (Pb-Free)	1500 / Tape & Reel
NVMFS6B03NWFT1G	6B03WF	DFN5 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS6B03NT3G	6B03	DFN5 (Pb-Free)	5000 / Tape & Reel
NVMFS6B03NWFT3G	6B03WF	DFN5 (Pb-Free, Wettable Flanks)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

PACKAGE DIMENSIONS

DFN5 5x6, 1.27P (SO-8FL) CASE 488AA ISSUE M



*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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